TOSHIBA Field Effect Transistor Silicon N Channel MOS Type

SSM3K116TU

High Speed Switching Applications

• 2.5V drive

• Low on-resistance: $R_{on} = 135m\Omega \text{ (max) (@V_{GS} = 2.5 V)}$

 $R_{on} = 100 m\Omega \text{ (max) } (@V_{GS} = 4.5 \text{ V})$

Lead(Pb)-free

Maximum Ratings (Ta = 25°C)

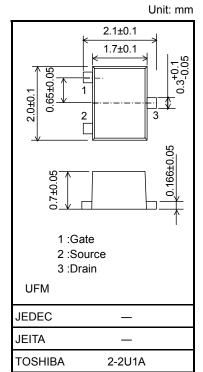
Characteristic		Symbol	Rating	Unit	
Drain-Source voltage		V_{DS}	30	V	
Gate-Source voltage		V_{GSS}	± 12	V	
Drain current	DC	ΙD	2.2	А	
	Pulse	I _{DP}	4.4		
Drain power dissipation		P _{D (Note1)}	800	mW	
		P _{D (Note2)}	500		
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	−55~150	°C	

Note1: Mounted on ceramic board.

 $(25.4 \text{ mm} \times 25.4 \text{ mm} \times 0.8 \text{ mm}, \text{ Cu Pad: } 645 \text{ mm}^2)$

Note2: Mounted on FR4 board.

 $(25.4 \text{ mm} \times 25.4 \text{ mm} \times 1.6 \text{ mm}, \text{Cu Pad: } 645 \text{ mm}^2)$



Weight: 6.6 mg (typ.)

Electrical Characteristics (Ta = 25°C)

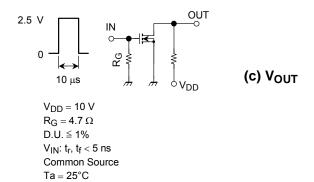
Charact	teristic	Symbol	Test Conditions	Min	Тур.	Max	Unit
Drain-Source breakdown voltage		V (BR) DSS	$I_D = 1 \text{ mA}, V_{GS} = 0$	30	_	_	V
		V (BR) DSX	$I_D = 1 \text{ mA}, V_{GS} = -12 \text{ V}$	18	_	_	
Drain cut-off curren	nt	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0$	_	_	1	μА
Gate leakage curre	ent	I _{GSS}	$V_{GS} = \pm 12V, V_{DS} = 0$	_	_	±1	μΑ
Gate threshold volt	age	V_{th}	$V_{DS} = 3 \text{ V}, I_{D} = 0.1 \text{ mA}$	0.5	_	1.1	V
Forward transfer ad	dmittance	Y _{fs}	$V_{DS} = 3 \text{ V}, I_{D} = 0.25 \text{ A}$ (Note3)	1	2	_	S
Drain-Source on-resistance		R _{DS (ON)}	$I_D = 0.5 \text{ A}, V_{GS} = 4.5 \text{ V}$ (Note3)		75	100	- mΩ
			$I_D = 0.25 \text{ A}, V_{GS} = 2.5 \text{ V}$ (Note3)	_	95	135	
Input capacitance		C _{iss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	245	_	pF
Output capacitance C_{OSS} $V_{DS} = 10 \text{ V}, V_{C}$		V _{DS} = 10 V, V _{GS} = 0, f = 1 MHz	_	41	_	pF	
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0, f = 1 MHz	_	33	_	pF
Switching time	Turn-on time	t _{on}	$V_{DD} = 10 \text{ V}, I_D = 0.25 \text{ A},$	_	9	_	ns
	Turn-off time	t _{off}	$V_{GS} = 0 \sim 2.5 \text{ V}, R_G = 4.7 \Omega$	_	15	_	
Drain-Source forwa	ard voltage	V _{DSF}	$I_D = -2.2A, V_{GS} = 0 V$ (Note3)	_	-0.83	-1.2	٧

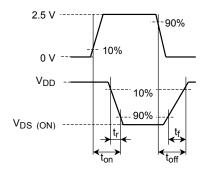
Note3: Pulse test

Switching Time Test Circuit

(a) Test Circuit

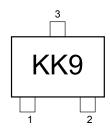


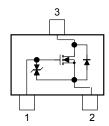




Marking

Equivalent Circuit (top view)





Precaution

 V_{th} can be expressed as the voltage between gate and source when the low operating current value is I_D =0.1mA for this product. For normal switching operation, $V_{GS\ (on)}$ requires a higher voltage than V_{th} , and $V_{GS\ (off)}$ requires a lower voltage than V_{th} .

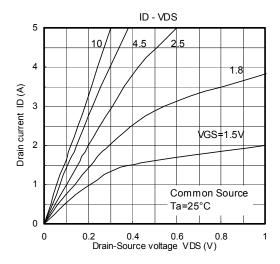
(The relationship can be established as follows: $V_{GS (off)} < V_{th} < V_{GS (on)}$)

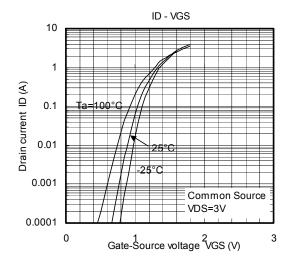
Take this into consideration when using the device.

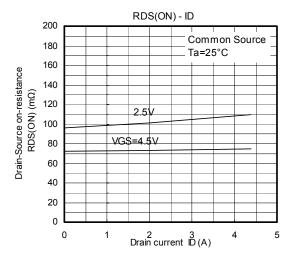
The recommended VGS voltage for turning on this product is 2.5 V or higher.

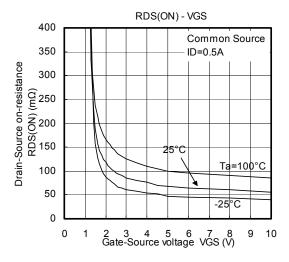
Handling Precaution

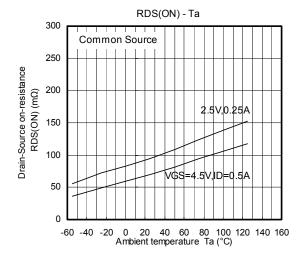
When handling individual devices which are not yet mounted on a circuit board, be sure that the environment is protected against electrostatic discharge. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.

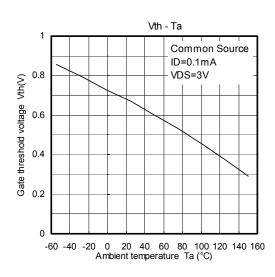


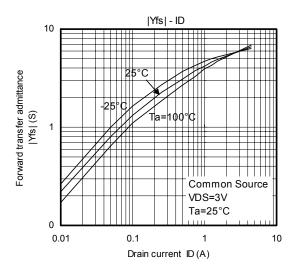


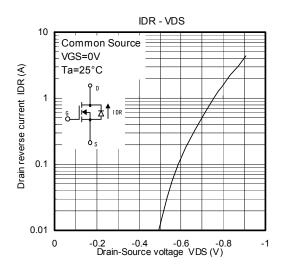


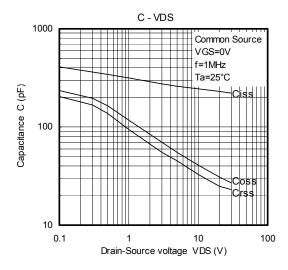


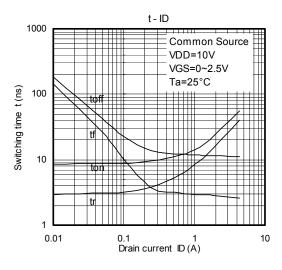


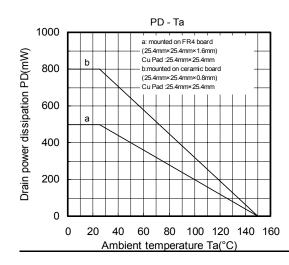


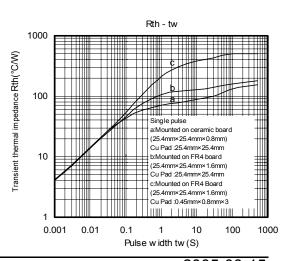












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Handbook" etc..

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